

<b>Notice of References Cited</b>	Application/Control No. 10/584,411		Applicant(s)/Patent Under Reexamination KIM, HAK-YONG	
	Examiner Leo B. Tentoni		Art Unit 1791	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0100725 A1	08-2002	Lee et al.	210/503
*	B	US-2004/0054406 A1	03-2004	Dubson et al.	623/001.39
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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